

MOSFET

Metal Oxide Semiconductor Field Effect Transistor

CoolMOS™ C6 600V

600V CoolMOS™ C6 Power Transistor
IPD60R1K4C6

Data Sheet

Rev. 2.3
Final

1 Description

CoolMOS™ is a revolutionary technology for high voltage power MOSFETs, designed according to the superjunction (SJ) principle and pioneered by Infineon Technologies. CoolMOS™ C6 series combines the experience of the leading SJ MOSFET supplier with high class innovation. The resulting devices provide all benefits of a fast switching SJ MOSFET while not sacrificing ease of use. Extremely low switching and conduction losses make switching applications even more efficient, more compact, lighter, and cooler.

Features

- Extremely low losses due to very low FOM $R_{DS(on)} \cdot Q_g$ and E_{oss}
- Very high commutation ruggedness
- Easy to use/drive
- Fully qualified according to JEDEC for Industrial Applications
- Halogen free mold compound, Pb-free plating

Applications

PFC stages, hard switching PWM stages and resonant switching PWM stages for e.g. PC Silverbox, Adapter, LCD & PDP TV, Lighting, Server, Telecom and UPS.

Please note:

For MOSFET paralleling the use of ferrite beads on the gate or separate totem poles is generally recommended.

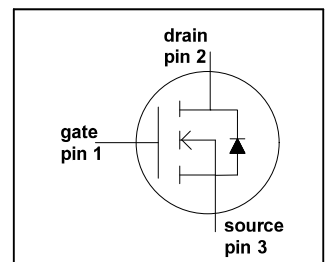
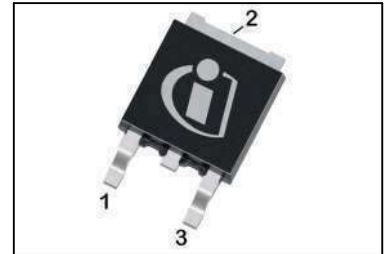


Table 1 Key Performance Parameters

Parameter	Value	Unit
$V_{DS} @ T_{j,max}$	650	V
$R_{DS(on),max}$	1.4	Ω
$Q_{g,typ}$	9.4	nC
$I_{D,pulse}$	8	A
$E_{oss} @ 400V$	1	μJ
Body diode di/dt	500	A/ μs

Type / Ordering Code	Package	Marking	Related Links
IPD60R1K4C6	PG-TO252	6R1K4C6	IFX C6 Product Brief IFX C6 Portfolio IFX CoolMOS Webpage IFX Design tools

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2 Maximum Ratings

at $T_j = 25\text{ °C}$, unless otherwise specified.

Table 2 Maximum ratings

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Continuous drain current ¹⁾	I_D	-	-	3.2	A	$T_C = 25\text{ °C}$
				2.0		$T_C = 100\text{ °C}$
Pulsed drain current ²⁾	$I_{D,pulse}$	-	-	8	A	$T_C = 25\text{ °C}$
Avalanche energy, single pulse	E_{AS}	-	-	26	mJ	$I_D = 0.6\text{ A}, V_{DD} = 50\text{ V}$ (see table 17)
Avalanche energy, repetitive	E_{AR}	-	-	0.09		$I_D = 0.6\text{ A}, V_{DD} = 50\text{ V}$
Avalanche current, repetitive	I_{AR}	-	-	0.6	A	
MOSFET dv/dt ruggedness	dv/dt	-	-	50	V/ns	$V_{DS} = 0 \dots 480\text{ V}$
Gate source voltage	V_{GS}	-20	-	20	V	static
		-30		30		AC ($f > 1\text{ Hz}$)
Power dissipation	P_{tot}	-	-	28.4	W	$T_C = 25\text{ °C}$
Operating and storage temperature	T_j, T_{stg}	-55	-	150	°C	
Continuous diode forward current	I_S	-	-	2.8	A	$T_C = 25\text{ °C}$
Diode pulse current ²⁾	$I_{S,pulse}$	-	-	8	A	$T_C = 25\text{ °C}$
Reverse diode dv/dt ³⁾	dv/dt	-	-	15	V/ns	$V_{DS} = 0 \dots 480\text{ V}, I_{SD} \leq I_D,$ $T_j = 25\text{ °C}$
Maximum diode commutation speed ³⁾	di/dt			500	A/ μ s	(see table 18)

1) Limited by $T_{j,max}$. Maximum duty cycle $D = 0.75$

2) Pulse width t_p limited by $T_{j,max}$

3) Identical low side and high side switch with identical R_G

3 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Thermal resistance, junction - case	R_{thJC}	-	-	4.4	°C/W	
Thermal resistance, junction - ambient	R_{thJA}	-	-	62		SMD version, device on PCB, minimal footprint
			35			SMD version, device on PCB, 6cm ² cooling area ¹⁾
Soldering temperature, wave- & reflowsoldering allowed	T_{sold}	-	-	260	°C	reflow MSL1

1) Device on 40mm*40mm*1.5 epoxy PCB FR4 with 6cm² (one layer, 70µm thick) copper area for drain connection. PCB is vertical without air stream cooling

4 Electrical characteristics

Electrical characteristics, at $T_J=25\text{ °C}$, unless otherwise specified

Table 4 Static characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Drain-source breakdown voltage	$V_{(BR)DSS}$	600	-	-	V	$V_{GS}=0\text{ V}, I_D=0.25\text{ mA}$
Gate threshold voltage	$V_{GS(th)}$	2.5	3	3.5		$V_{DS}=V_{GS}, I_D=0.09\text{ mA}$
Zero gate voltage drain current	I_{DSS}	-	-	1	μA	$V_{DS}=600\text{ V}, V_{GS}=0\text{ V}, T_J=25\text{ °C}$
		-	10	-		$V_{DS}=600\text{ V}, V_{GS}=0\text{ V}, T_J=150\text{ °C}$
Gate-source leakage current	I_{GSS}	-	-	100	nA	$V_{GS}=20\text{ V}, V_{DS}=0\text{ V}$
Drain-source on-state resistance	$R_{DS(on)}$	-	1.26	1.4	Ω	$V_{GS}=10\text{ V}, I_D=1.1\text{ A}, T_J=25\text{ °C}$
		-	3.28	-		$V_{GS}=10\text{ V}, I_D=1.1\text{ A}, T_J=150\text{ °C}$
Gate resistance	R_G	-	14	-	Ω	$f=1\text{ MHz}, \text{open drain}$

Table 5 Dynamic characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition	
		Min.	Typ.	Max.			
Input capacitance	C_{iss}	-	200	-	pF	$V_{GS}=0\text{ V}, V_{DS}=100\text{ V}, f=1\text{ MHz}$	
Output capacitance	C_{oss}	-	16	-			
Effective output capacitance, energy related ¹⁾	$C_{o(er)}$	-	11	-			$V_{GS}=0\text{ V}, V_{DS}=0\dots480\text{ V}$
Effective output capacitance, time related ²⁾	$C_{o(tr)}$	-	41.3	-			$I_D=\text{constant}, V_{GS}=0\text{ V}, V_{DS}=0\dots480\text{ V}$
Turn-on delay time	$t_{d(on)}$	-	8	-	ns	$V_{DD}=400\text{ V}, V_{GS}=10\text{ V}, I_D=1.4\text{ A}, R_G=12.2\text{ }\Omega$ (see table 16)	
Rise time	t_r	-	7	-			
Turn-off delay time	$t_{d(off)}$	-	40	-			
Fall time	t_f	-	20	-			

1) $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(BR)DSS}$

2) $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(BR)DSS}$

Table 6 Gate charge characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gate to source charge	Q_{gs}	-	1.1	-	nC	$V_{DD}=480\text{ V}$, $I_D=1.4\text{ A}$, $V_{GS}=0\text{ to }10\text{ V}$
Gate to drain charge	Q_{gd}	-	5	-		
Gate charge total	Q_g	-	9.4	-		
Gate plateau voltage	$V_{plateau}$	-	5.4	-	V	

Table 7 Reverse diode characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Diode forward voltage	V_{SD}	-	0.9	-	V	$V_{GS}=0\text{ V}$, $I_F=1.4\text{ A}$, $T_j=25\text{ °C}$
Reverse recovery time	t_{rr}	-	230	-	ns	$V_R=400\text{ V}$, $I_F=1.4\text{ A}$, $di_F/dt=100\text{ A}/\mu\text{s}$ (see table 18)
Reverse recovery charge	Q_{rr}	-	1.1	-	μC	
Peak reverse recovery current	I_{rrm}	-	9.8	-	A	

5 Electrical characteristics diagrams

Table 8

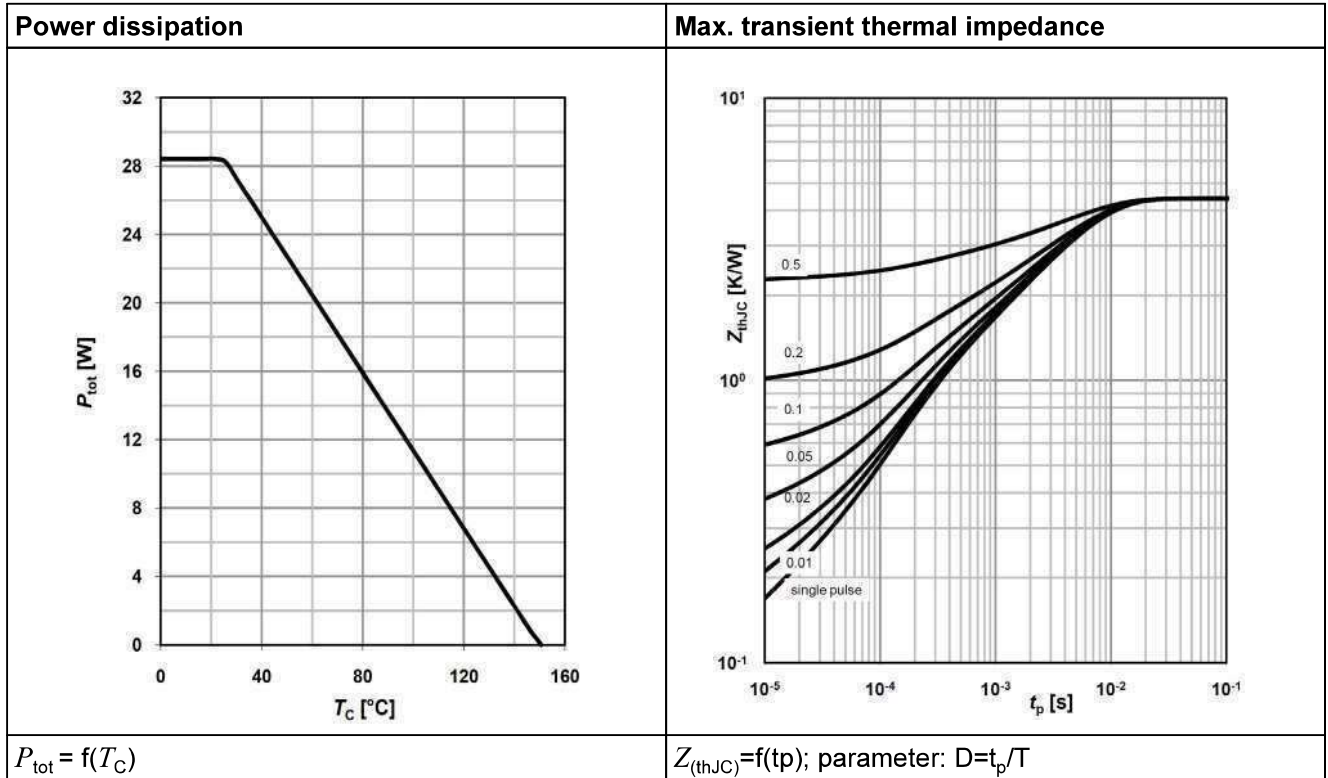


Table 9

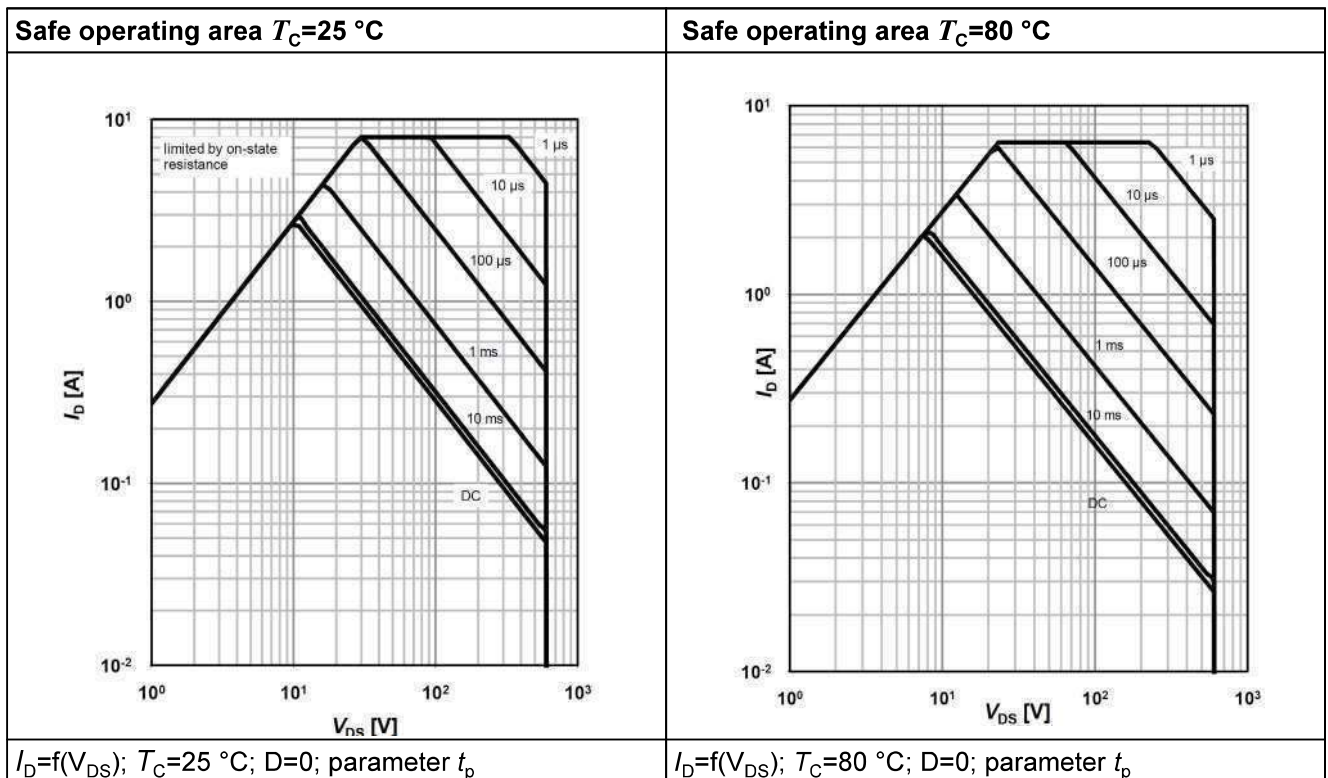


Table 10

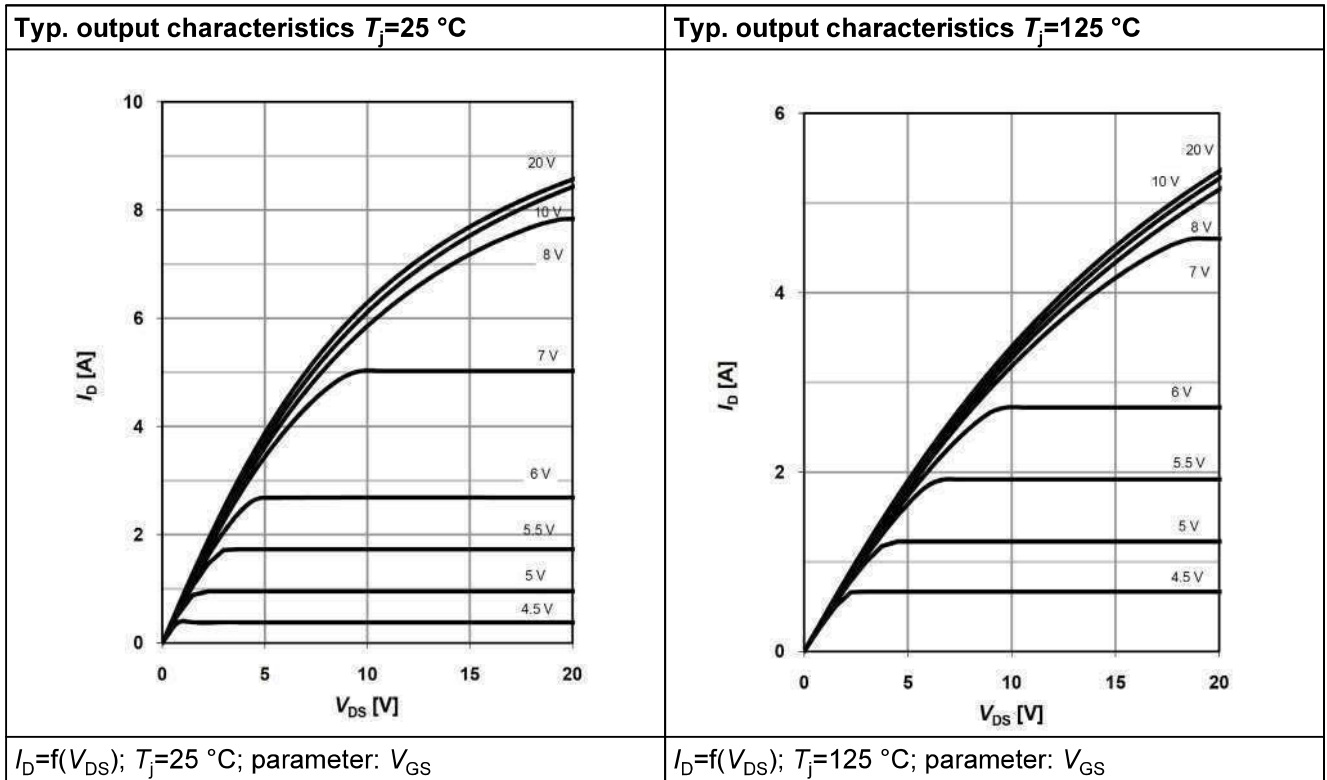


Table 11

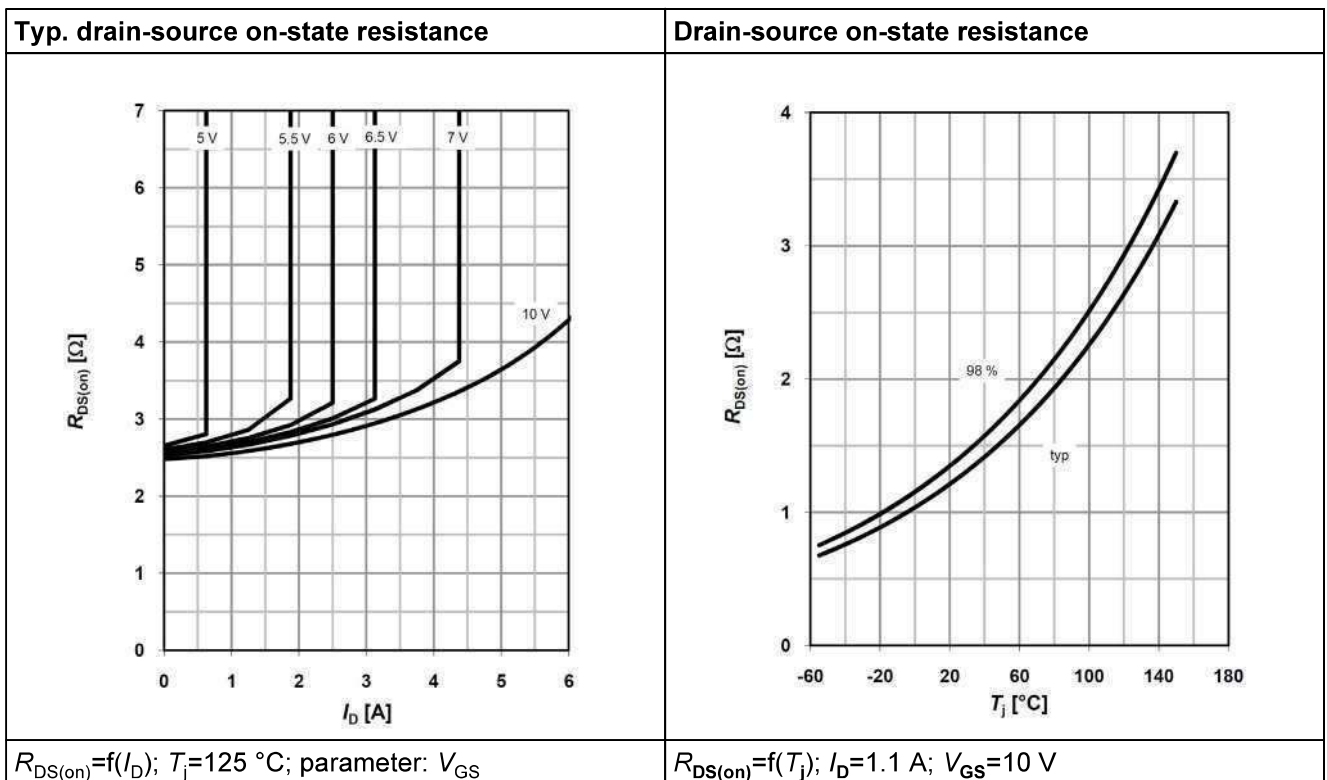


Table 12

Typ. transfer characteristics	Typ. gate charge
$I_D = f(V_{GS}); V_{DS} = 20V$	$V_{GS} = f(Q_{gate}); I_D = 1.4 A \text{ pulsed}$

Table 13

Avalanche energy	Drain-source breakdown voltage
$E_{AS} = f(T_j); I_D = 0.6 A; V_{DD} = 50 V$	$V_{BR(DSS)} = f(T_j); I_D = 0.25 mA$

Table 14

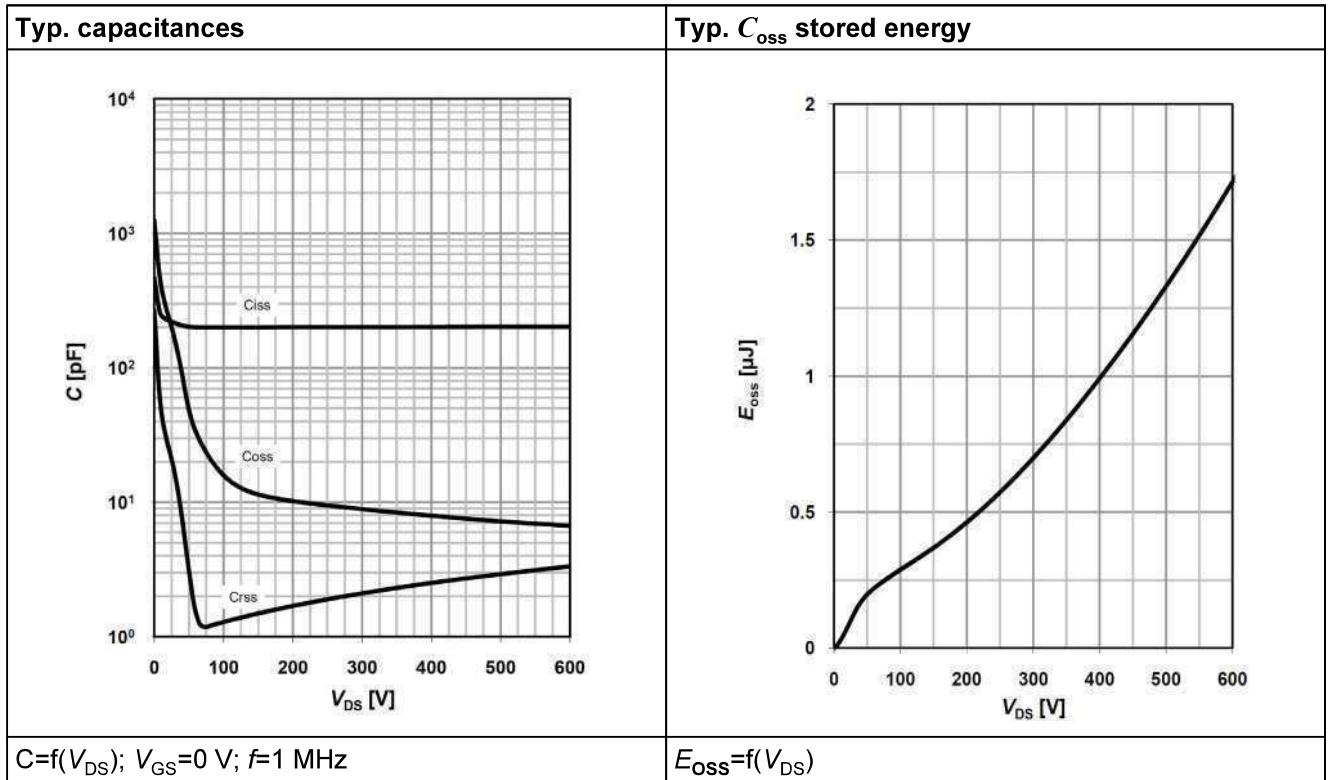
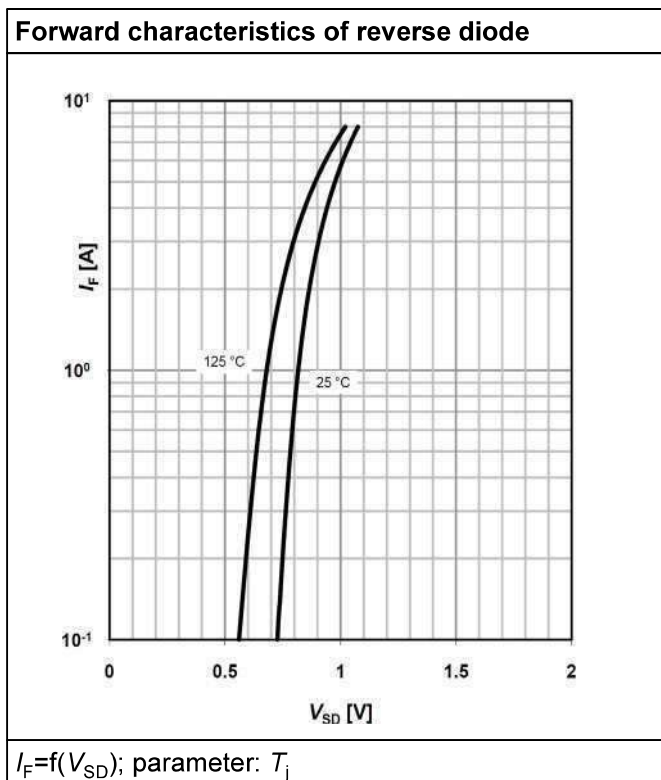
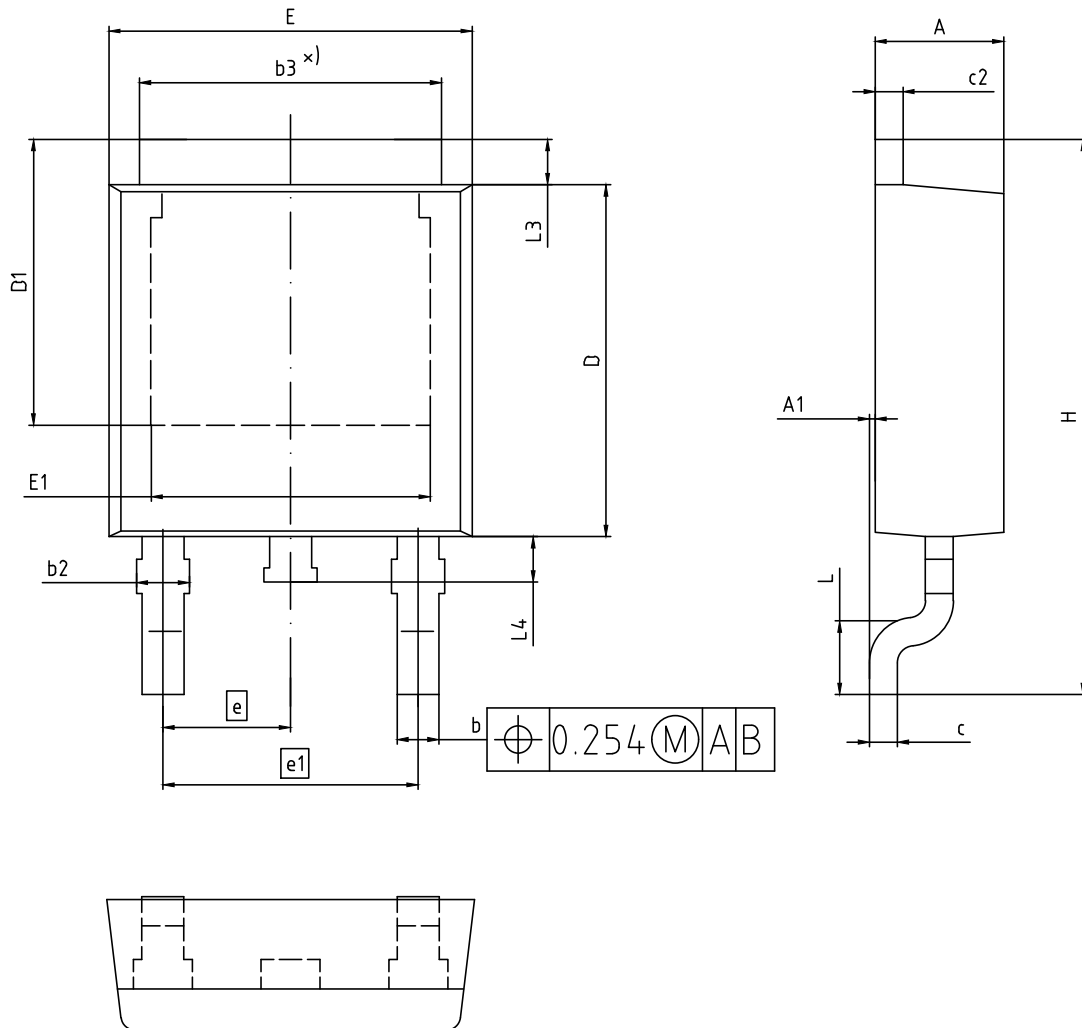


Table 15



7 Package outlines



ALL DIMENSIONS REFER TO JEDEC STANDARD TO-252 AND DO NOT INCLUDE MOLD FLASH OR PROTRUSIONS.

DIMENSION	MILLIMETERS	
	MIN.	MAX.
A	2.16	2.41
A1	0.00	0.15
b	0.64	0.89
b2	0.65	1.15
b3	4.95	5.50
c	0.46	0.61
c2	0.40	0.98
D	5.97	6.22
D1	5.02	5.84
E	6.35	6.73
E1	4.32	5.50
e	2.29	
e1	4.57	
N	3	
H	9.40	10.48
L	1.18	1.78
L3	0.89	1.27
L4	0.51	1.02

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Figure 1 Outlines TO-252, dimensions in mm

Revision History

IPD60R1K4C6

Revision: 2020-05-20, Rev. 2.3

Previous Revision

Revision	Date	Subjects (major changes since last revision)
1.1	2011-06-08	Release of final data sheet
2.0	2011-06-08	Release of final data sheet
2.1	2011-09-14	-
2.2	2015-11-17	Added Halogen Free info
2.3	2020-05-20	Update of the package outlines

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